

Figure 1
(Prior Art)

TITLE: TEST UNIT AND ENCLOSURE FOR TESTING INTEGRATED CIRCUITS
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Dkt #: 884.295US2

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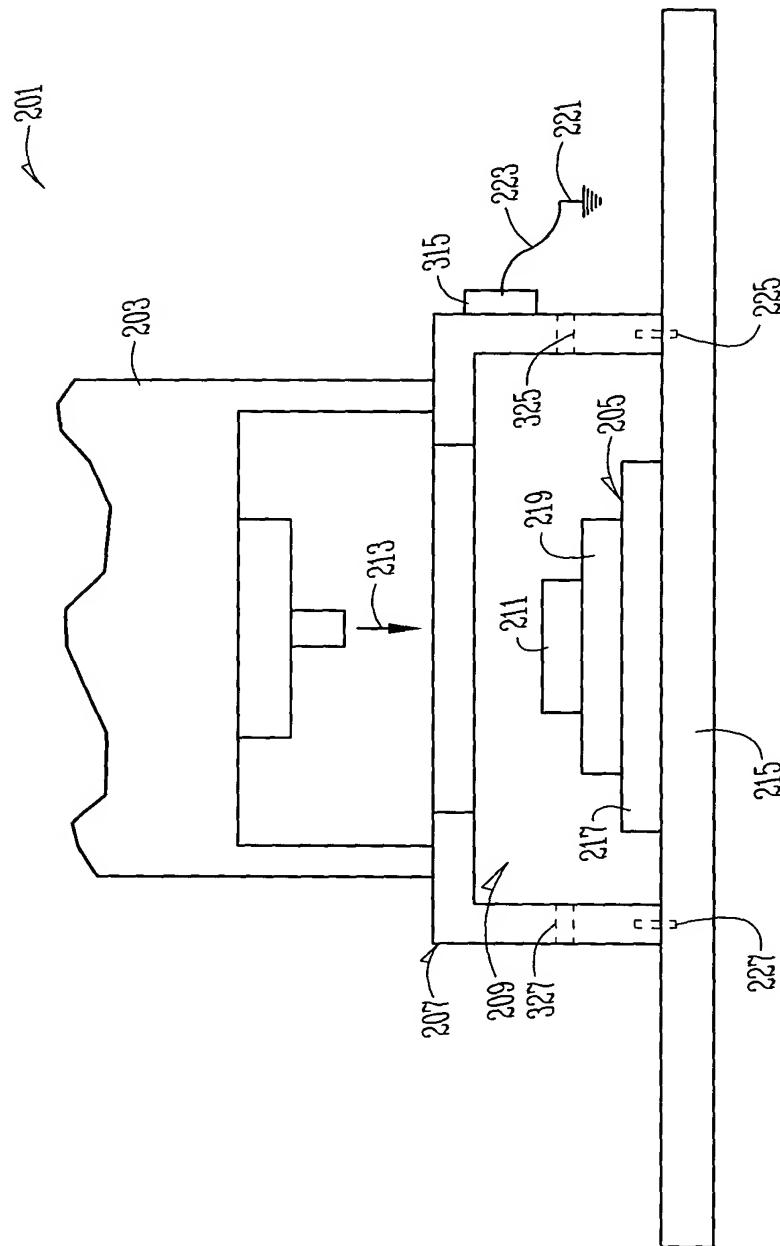


Figure 2

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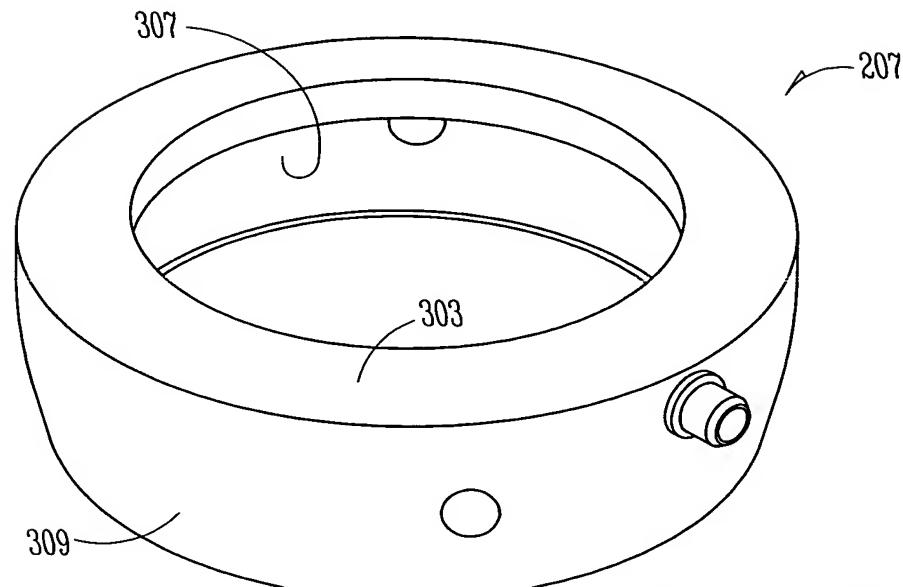


Figure 3A

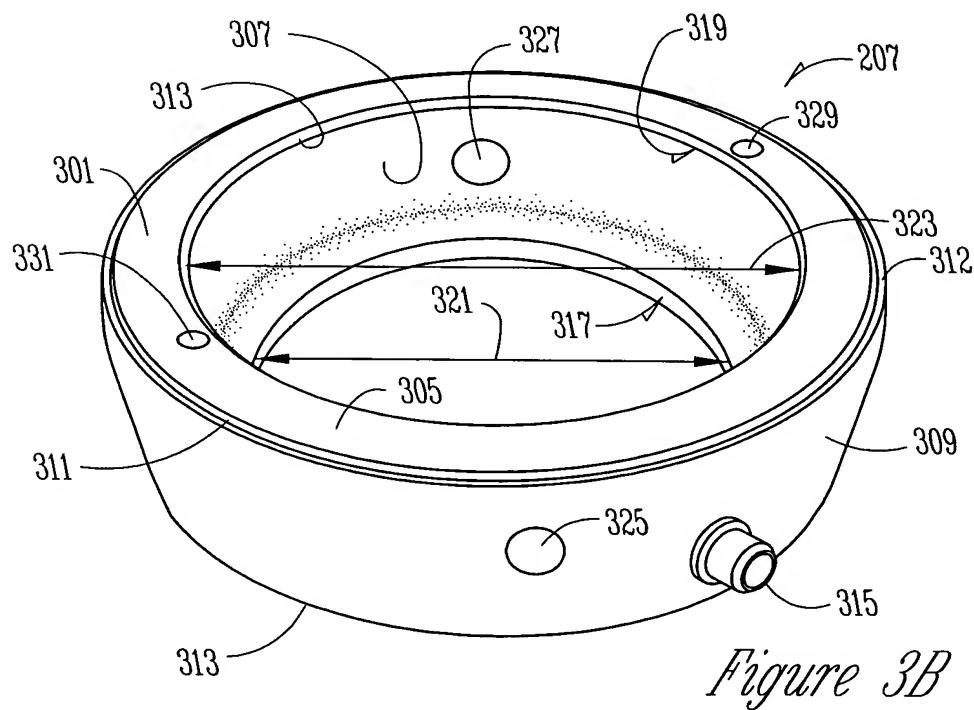


Figure 3B